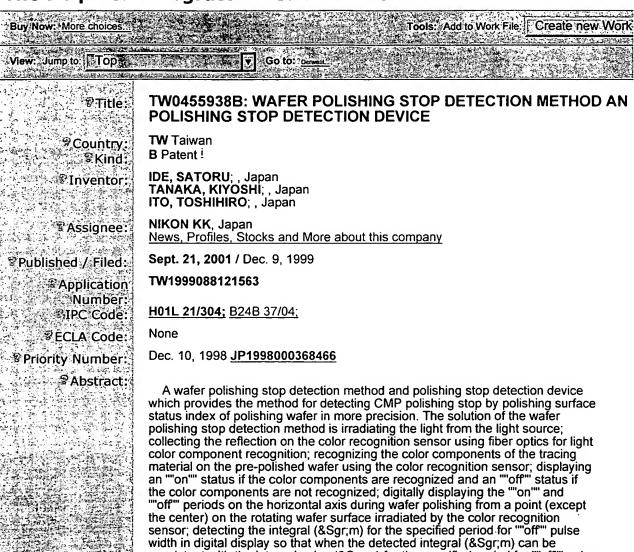


The Delphion Integrated View: INPADOC Record

polishing stop.



consistent with the integral value (&Sgr;n) for the specified period for ""off" pulse width of predetermined best wafer polishing stop, defining it as the wafer

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Buy PDF	Publication	Pub. Date	Filed	Title	
	US6342166B1	Jan. 29, 2002			
A	<u>US6342166</u>	Jan. 29, 2002	Dec. 6, 1999	Method of detecting end point of p wafer and apparatus for detecting polishing	
	TW0455938B	Sept. 21, 2001	Dec. 9, 1999	WAFER POLISHING STOP DETE METHOD AND POLISHING STOP DEVICE	
	KR0048040A		Dec. 9, 1999	METHOD FOR DETECTING POLI POINT OF WAFER AND APPARA DETECTING THE POLISHING EN	
	JP2000183002A2	June 30, 2000	Dec. 10, 1998	METHOD AND DEVICE FOR DET WAFER POLISH END-POINT	
5 family members shown above					

E Other Abstract Info: Inquire Regarding



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